



Converting Ball Grid Array Components to Column Grid Array

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Introduction

- The availability of Military-grade electronics is declining
- Ball Grid Array (BGA) is rapidly becoming the package style of choice in commercial electronics
- For Military and Space environments, BGA packaging is a reliability compromise (BGAs lack compliant leads)
- Modifications and ruggedization of packaging is essential for ensuring reliability of military electronics⁴

The Problem



Typical temp-cycle failure in high-lead ball¹

- Solder balls are less compliant than leads
- Stress is induced by:
 - Coefficient of Thermal Expansion (CTE) mismatch (temperature cycle)
 - Thermal mismatch (power cycle)
 - Mechanical (warp, vibration, etc)
- Stress increases with:
 - Distance from neutral point (larger packages)
 - Lower standoff height

Types of Columns



Wire Column

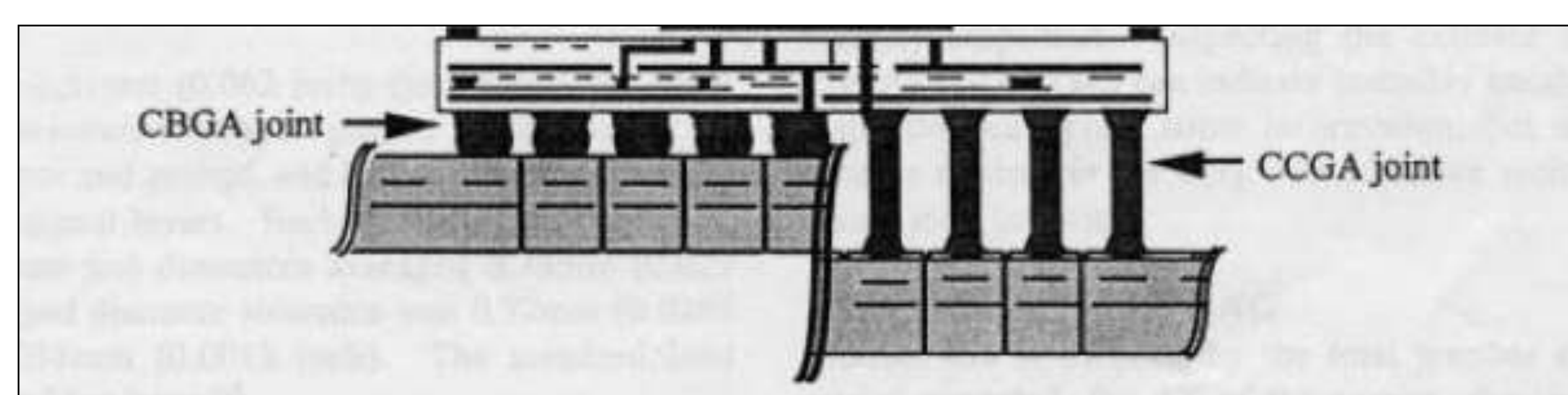
High-Lead wire attached with Sn63-Pb37 fillets



Reinforced Solder Column

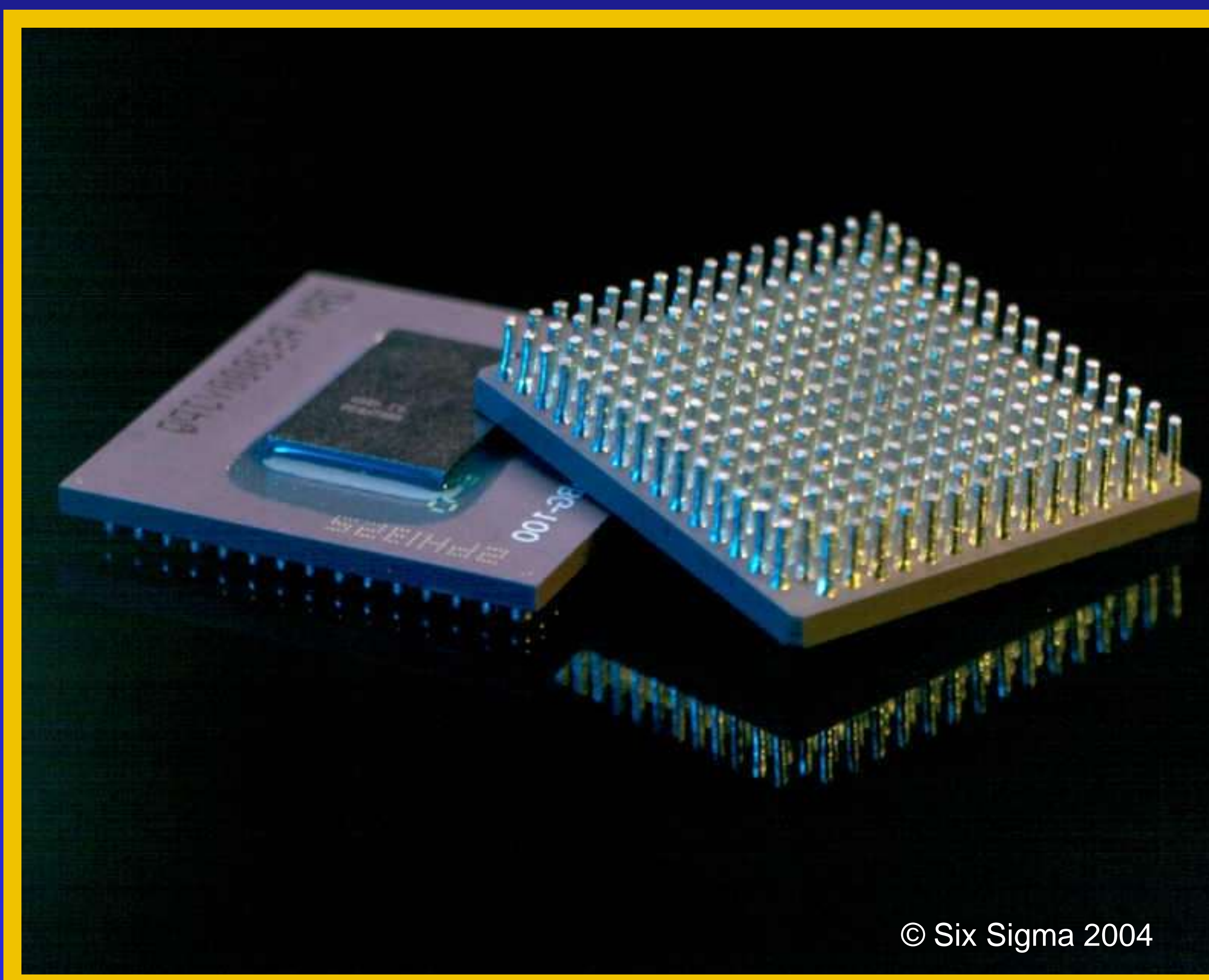
High-Lead wire core with spiral wrapped copper ribbon attached with Sn63-Pb37 fillets

BGA vs. CGA



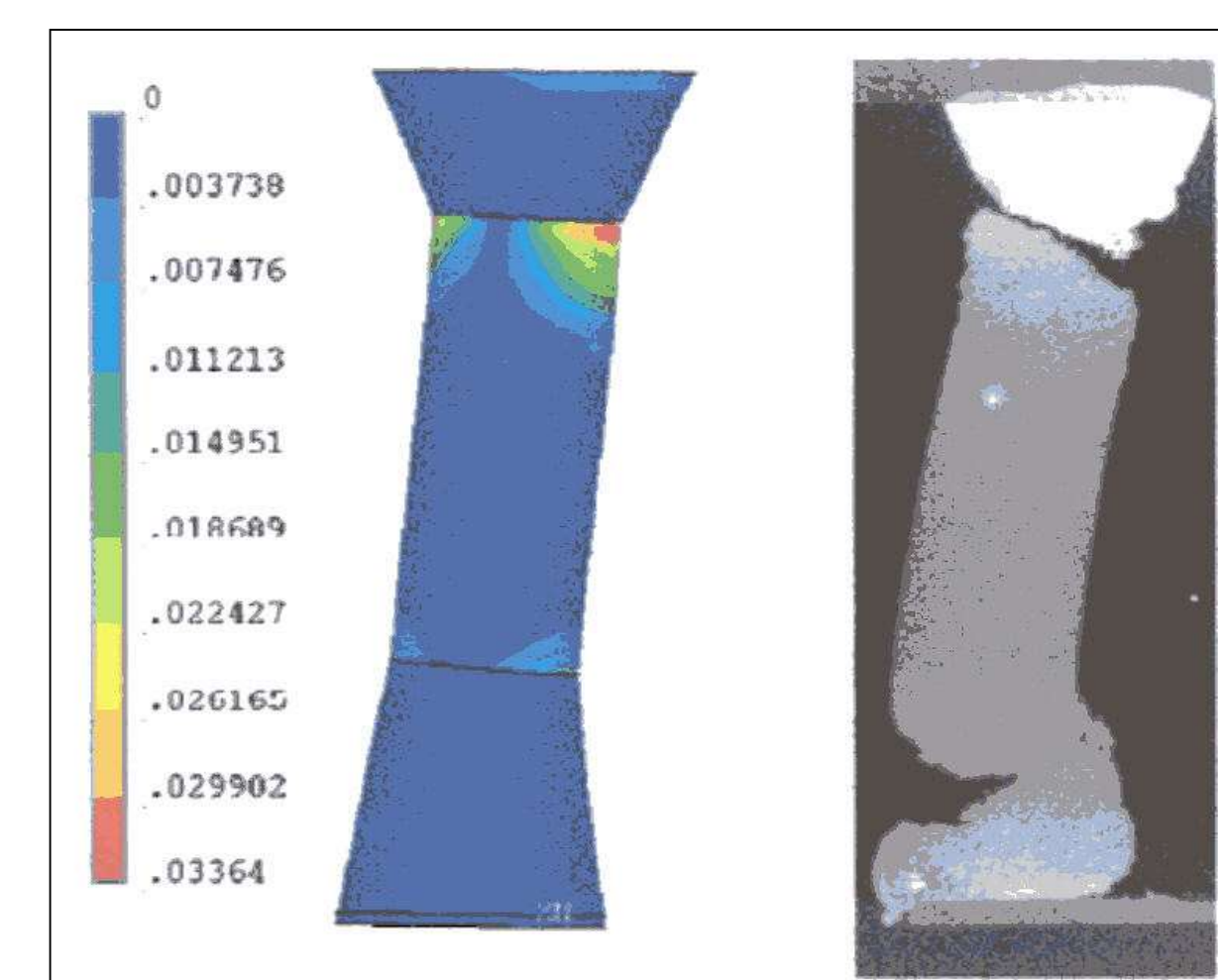
Ball Grid Array vs. Column Grid Array¹

- Column Grid Array (CGA) is a flexible interconnect replacement for rigid solder balls
- Higher standoff and compliance in the column alleviates CTE and thermal mismatch between the board and the component



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Benefits of the Reinforced Column



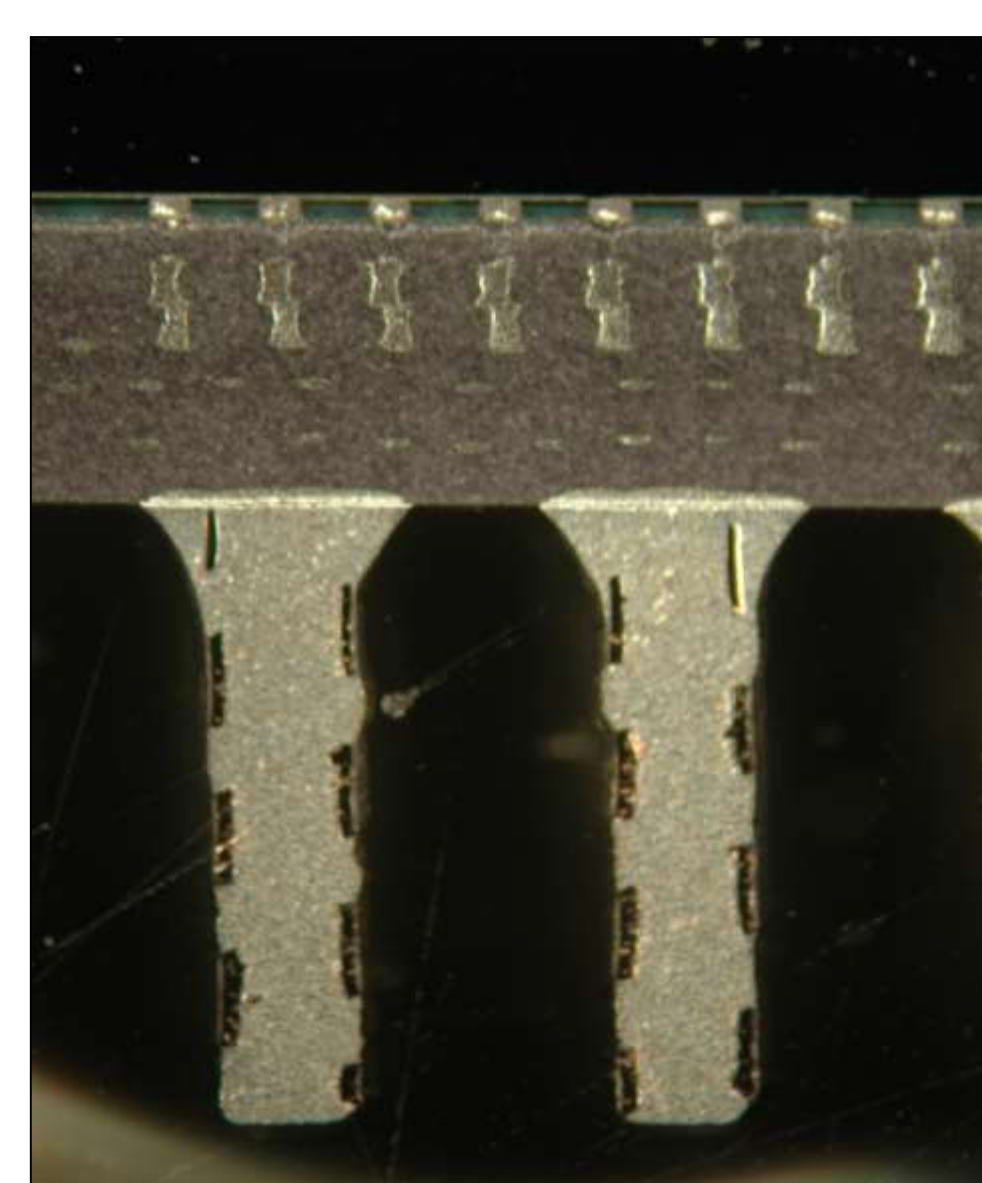
Georgia Institute of Technology & IBM²

Straight Wire Column

- Finite element model showing location of maximum strain (Left)
- Typical failure of non-reinforced column (Right)

Copper Reinforced Column

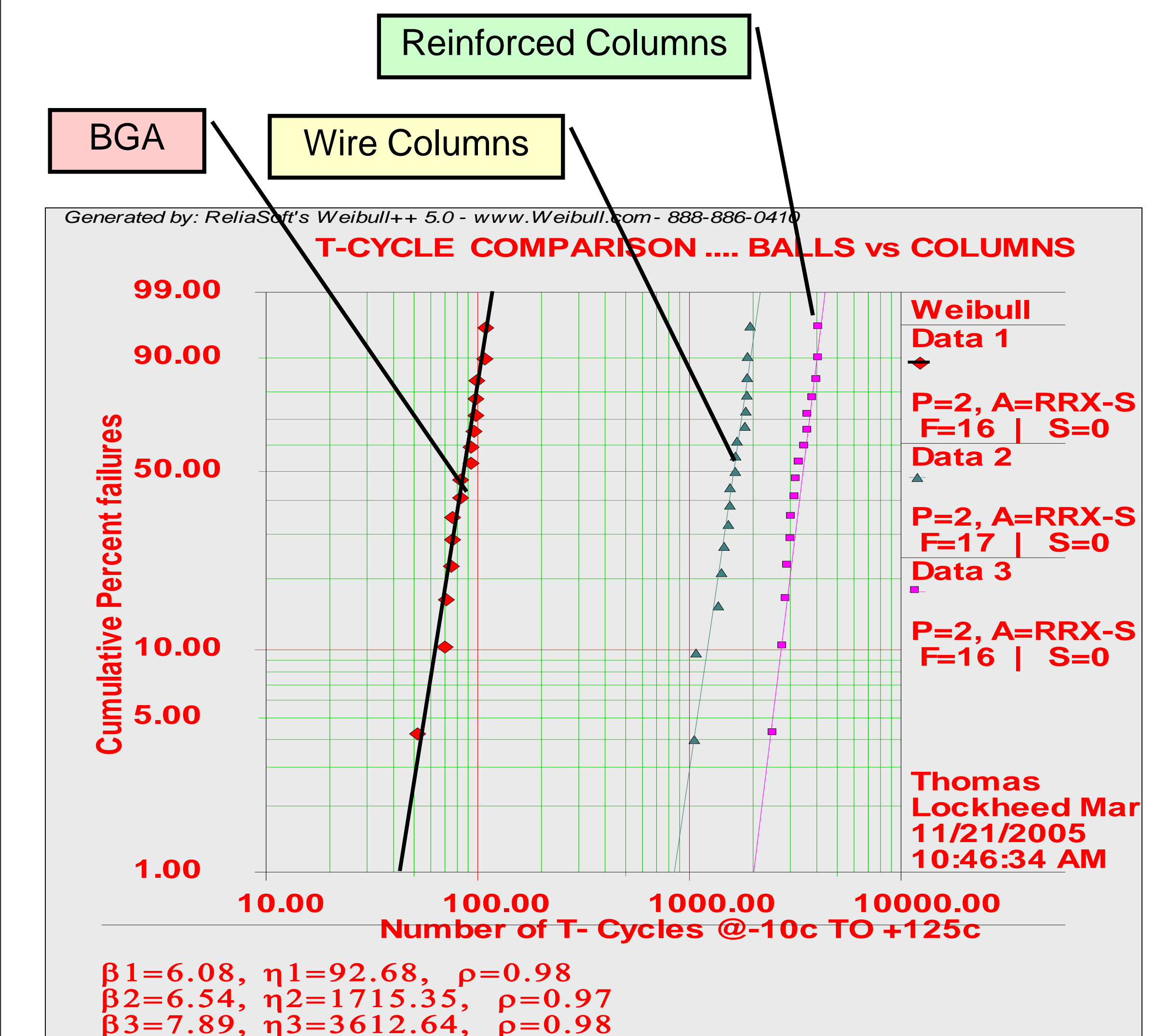
- Crack propagation abated
- Redundancy without stiffness
- Continues to function electrically even if core is cracked



Test Results

Temperature Cycles -10 to +125 C
All parts ceramic with 1.27mm pitch
625 pin package 32mm square

CBGA625	BGA with high-Pb spheres
CCGA625	CGA with straight wire columns
CCGA625R	CGA with reinforced columns



Temperature Cycle Test Results - Lockheed Martin³

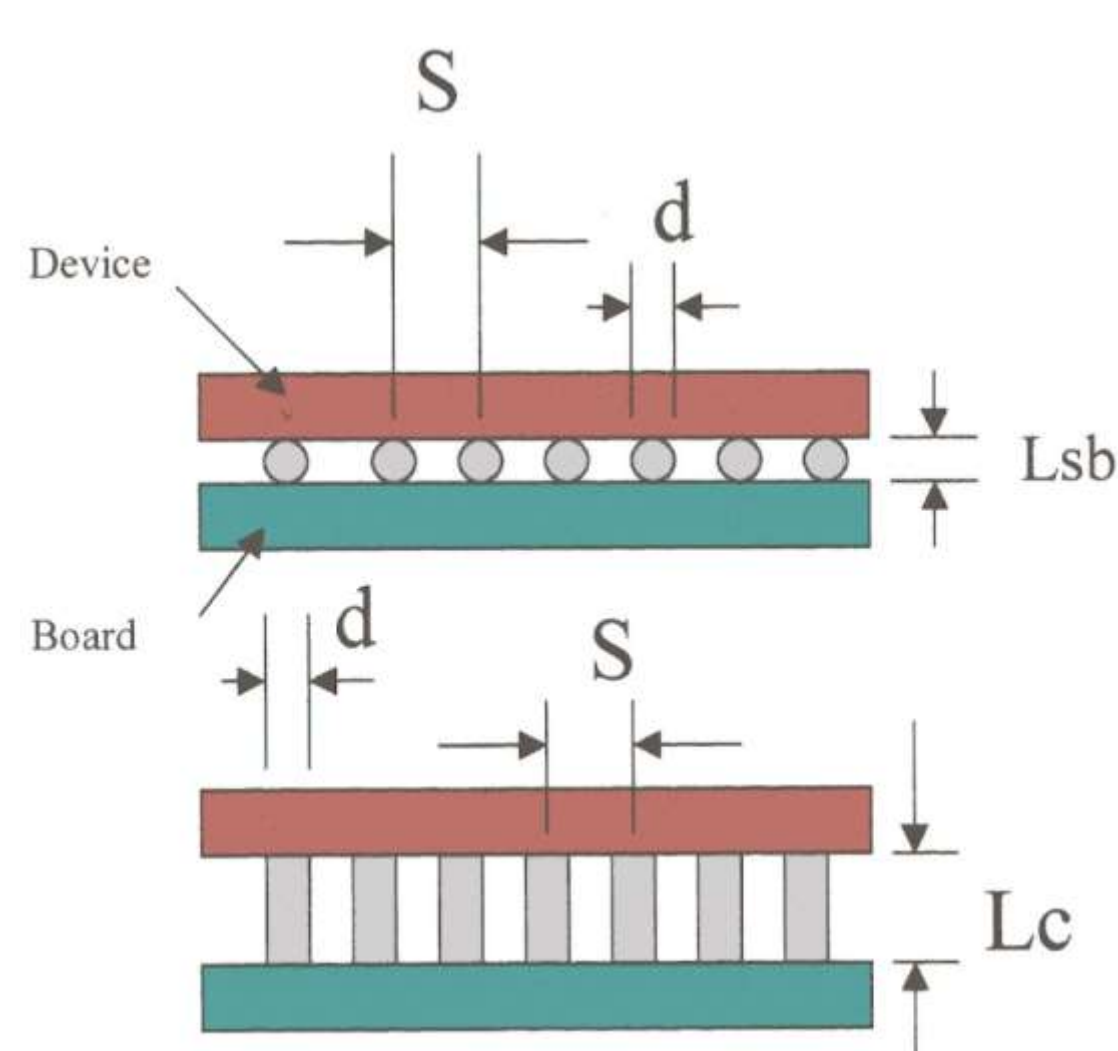
Conclusion

- Many commercial components are not capable of meeting the environmental requirements of military and space applications
- CGA modifications to commercial devices result in
 - Reliability Improvements
 - Robust Designs
- Reinforced solder columns show a significant performance advantage in comparison to other solder columns

Future Work

- Military funding of this technology will allow significant improvements such as:
 - Optimize column design through finite element modeling and analysis of the reinforced column
 - Reliability testing and qualification of enhancements in design and materials
 - Development of a lead-free version

The CGA Solution



ΔT_1 = Temperature Change of Board
 ΔT_2 = Temperature Change of Component
 α_1 = CTE of the Board
 α_2 = CTE of the Component
 S = Distance from Neutral Point (DNP)
 E = Modulus of Elasticity of Ball or Column
 d = Diameter of Ball or Column
 L = Standoff Height of Ball or Column
 σ_{max} = Maximum Stress

$$\sigma_{max} \approx \frac{1.5 \cdot (\alpha_1 \cdot \Delta T_1 - \alpha_2 \cdot \Delta T_2) (S \cdot E \cdot d)}{L^2}$$

Acknowledgments

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